

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



# Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China









## STGD6M65DF2

# Trench gate field-stop IGBT, M series 650 V, 6 A low loss

Datasheet - production data

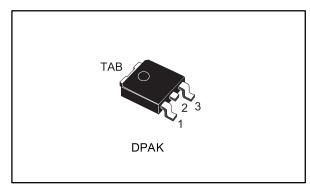
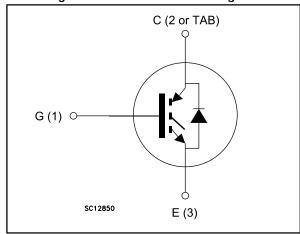


Figure 1: Internal schematic diagram



#### **Features**

- 6 μs of short-circuit withstand time
- $V_{CE(sat)} = 1.55 \text{ V (typ.)} @ I_C = 6 \text{ A}$
- Tight parameter distribution
- Safer paralleling
- Low thermal resistance
- Soft and very fast recovery antiparallel diode

### **Applications**

- Motor control
- UPS
- PFC

## **Description**

This device is an IGBT developed using an advanced proprietary trench gate field-stop structure. The device is part of the M series IGBTs, which represent an optimal balance between inverter system performance and efficiency where low-loss and short-circuit functionality are essential. Furthermore, the positive V<sub>CE(sat)</sub> temperature coefficient and tight parameter distribution result in safer paralleling operation.

Table 1: Device summary

Order code	Marking	Package	Packing
STGD6M65DF2	G6M65DF2	DPAK	Tape and reel

STGD6M65DF2 Contents

## Contents

1	Electric	eal ratings	3
2		eal characteristics	
	2.1	Electrical characteristics (curves)	7
3	Test cir	cuits	12
4	Packag	e information	13
	4.1	DPAK (TO-252) type A2 package information	14
	4.2	DPAK (TO-252) packing information	17
5	Revisio	n history	19

STGD6M65DF2 Electrical ratings

# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
Vces	Collector-emitter voltage (V <sub>GE</sub> = 0 V)	650	V
1.	Continuous collector current at T <sub>C</sub> = 25 °C	12	Α
lc	Continuous collector current at T <sub>C</sub> = 100 °C	6	Α
ICP <sup>(1)</sup>	Pulsed collector current	24	Α
$V_{GE}$	Gate-emitter voltage	±20	V
	Continuous forward current at T <sub>C</sub> = 25 °C	12	Α
l <sub>F</sub>	Continuous forward current at T <sub>C</sub> = 100 °C	6	Α
I <sub>FP</sub> (1)	Pulsed forward current		Α
Ртот	Total dissipation at $T_C = 25$ °C 88		W
T <sub>STG</sub>	Storage temperature range - 55 to 150 °C		
$T_J$	Operating junction temperature range	- 55 to 175	°C

#### Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit	
RthJC	Thermal resistance junction-case IGBT	1.7	°C/W	
RthJC	R <sub>thJC</sub> Thermal resistance junction-case diode 5			
R <sub>thJA</sub>	R <sub>thJA</sub> Thermal resistance junction-ambient			

 $<sup>\</sup>ensuremath{^{(1)}}\mbox{Pulse}$  width limited by maximum junction temperature.

Electrical characteristics STGD6M65DF2

## 2 Electrical characteristics

T<sub>C</sub> = 25 °C unless otherwise specified

**Table 4: Static characteristics** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit	
V <sub>(BR)CES</sub>	Collector-emitter breakdown voltage	$V_{GE} = 0 \text{ V}, I_C = 250  \mu\text{A}$	650			٧	
		$V_{GE} = 15 \text{ V}, I_{C} = 6 \text{ A}$		1.55	2.0		
V <sub>CE(sat)</sub>	V <sub>CE(sat)</sub> Collector-emitter saturation	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 6 A, T <sub>J</sub> = 125 °C		1.9		V	
voltage	voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 6 A, T <sub>J</sub> = 175 °C		2.1			
		I <sub>F</sub> = 6 A		2.2			
$V_{F}$	Forward on-voltage	I <sub>F</sub> = 6 A, T <sub>J</sub> = 125 °C		2.0		V	
		I <sub>F</sub> = 6 A, T <sub>J</sub> = 175 °C		1.9			
$V_{\text{GE(th)}}$	Gate threshold voltage	$V_{CE} = V_{GE}$ , $I_C = 250 \mu A$	5	6	7	V	
I <sub>CES</sub>	Collector cut-off current	$V_{GE} = 0 \text{ V}, V_{CE} = 650 \text{ V}$			25	μΑ	
I <sub>GES</sub>	Gate-emitter leakage current	$V_{CE} = 0 \text{ V}, V_{GE} = \pm 20 \text{ V}$			±250	μΑ	

**Table 5: Dynamic characteristics** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Cies	Input capacitance		-	530	-	
C <sub>oes</sub>	Output capacitance	V <sub>CE</sub> = 25 V, f = 1 MHz, V <sub>GE</sub> = 0 V	-	31	ı	рF
Cres	Reverse transfer capacitance		-	11	1	
$Q_g$	Total gate charge		-	21.2	1	
Q <sub>ge</sub>	Gate-emitter charge	V <sub>CC</sub> = 520 V, I <sub>C</sub> = 6 A, V <sub>GE</sub> = 15 V (see <i>Figure 30: " Gate charge test</i>	-	5.2	-	nC
Qgc	Gate-collector charge	circuit")	-	8.8	-	

Table 6: IGBT switching characteristics (inductive load)

Table 6: IGBT switching characteristics (inductive load)						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time			15	-	ns
tr	Current rise time			5.8	ı	ns
(di/dt) <sub>on</sub>	Turn-on current slope			828	ı	A/μs
t <sub>d(off)</sub>	Turn-off-delay time	V 400 V I C A V 45 V		90	-	ns
tf	Current fall time	V <sub>CE</sub> = 400 V, I <sub>C</sub> = 6 A, V <sub>GE</sub> = 15 V, R <sub>G</sub> = 22 Ω (see Figure 29: "Test circuit for inductive load switching")		130	1	ns
E <sub>on</sub> <sup>(1)</sup>	Turn-on switching energy			0.036	ı	mJ
E <sub>off</sub> <sup>(2)</sup>	Turn-off switching energy			0.200	ı	mJ
E <sub>ts</sub>	Total switching energy			0.236	-	mJ
t <sub>d(on)</sub>	Turn-on delay time			17	-	ns
tr	Current rise time			7	ı	ns
(di/dt) <sub>on</sub>	Turn-on current slope			685	ı	A/μs
$t_{\text{d(off)}}$	Turn-off-delay time	V 400 V I 6 A V 15 V		86	-	ns
tf	Current fall time	$V_{CE} = 400 \text{ V}$ , $I_{C} = 6 \text{ A}$ , $V_{GE} = 15 \text{ V}$ , $R_{G} = 22 \Omega T_{J} = 175 ^{\circ}\text{C}$ (see Figure 29: "  Test circuit for inductive load switching")		205	-	ns
E <sub>on</sub> (1)	Turn-on switching energy	rest circuit for modelive load Switching )		0.064	-	mJ
E <sub>off</sub> <sup>(2)</sup>	Turn-off switching energy			0.290	-	mJ
E <sub>ts</sub>	Total switching energy			0.354	-	mJ
+.	Short-circuit	$V_{CC} \le 400 \text{ V}, V_{GE} = 15 \text{ V}, T_{Jstart} = 150 \text{ °C}$	6		-	μs
t <sub>sc</sub>	withstand time	V <sub>CC</sub> ≤ 400 V, V <sub>GE</sub> = 13 V, T <sub>Jstart</sub> = 150 °C	10		1	μs

#### Notes:

 $<sup>^{(1)}</sup>$ Turn-on switching energy includes reverse recovery of the diode.

 $<sup>\</sup>ensuremath{^{(2)}}\mbox{Turn-off}$  switching energy also includes the tail of the collector current.

Table 7: Diode switching characteristics (inductive load)

Cymbol	Parameter Test conditions				Mov	Unit
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
trr	Reverse recovery time		-	140	-	ns
Q <sub>rr</sub>	Reverse recovery charge		-	210	-	nC
I <sub>rrm</sub>	Reverse recovery current	IF = 6 A, VR = 400 V, VGE = 15 V (see Figure 29: " Test circuit for inductive load switching")	-	6.6	1	Α
dI <sub>rr</sub> /dt	Peak rate of fall of reverse recovery current during to	di/dt = 1000 A/μs	-	430	-	A/μs
Err	Reverse recovery energy			16	1	μJ
t <sub>rr</sub>	Reverse recovery time			200	ı	ns
Qrr	Reverse recovery charge		-	473	ı	nC
I <sub>rrm</sub>	Reverse recovery current	$I_F = 6 \text{ A}, V_R = 400 \text{ V}, V_{GE} = 15 \text{ V}$ $T_J = 175 \text{ °C (see } Figure 29: " Test circuit for inductive load switching")$		9.6	-	Α
dI <sub>rr</sub> /dt	Peak rate of fall of reverse recovery current during to	di/dt = 1000 A/μs	-	428	-	A/μs
Err	Reverse recovery energy		-	32	-	μJ

#### **Electrical characteristics (curves)** 2.1

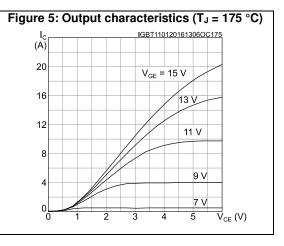
Figure 2: Power dissipation vs. case temperature IGBT110120161302PDT V<sub>GE</sub> ≥15 V, T<sub>J</sub> ≤175 °C 80 60 40 20 T<sub>C</sub> (°C)

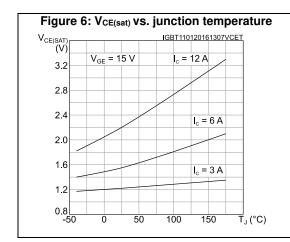
100

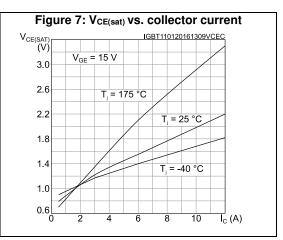
150

Figure 3: Collector current vs. case temperature IGBT110120161336CCT I<sub>C</sub> V<sub>GE</sub> ≥15 V, T<sub>J</sub> ≤175 °C 12 10 8 150 T<sub>c</sub> (°C)

Figure 4: Output characteristics (T<sub>J</sub> = 25 °C) IGBT110120161305OC25 I<sub>C</sub> (A) 13 V 20  $V_{GE}$  = 15 V16 11 V 12 9 V  $\vec{V}_{CE}\left(V\right)$ 







8

10<sup>0</sup>

Figure 8: Collector current vs. switching frequency

Ic IGBT110120161310CCS

(A)

16

T<sub>c</sub> = 80 °C

 $T_c = 100 \, ^{\circ}C$ 

f (kHz)

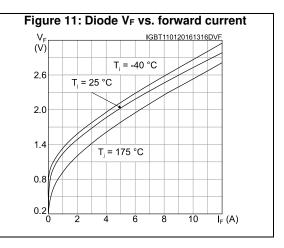
Rectangular current shape (duty cycle = 0.5,  $V_{cc}$  = 400 V  $R_{s}$  = 22  $\Omega$ ,  $V_{GE}$  = 0/15 V,

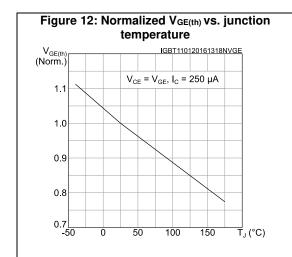
10<sup>1</sup>

10<sup>2</sup>

T = 175 °C

Figure 9: Forward bias safe operating area  $\begin{array}{c} I_{C} \\ I_{$ 





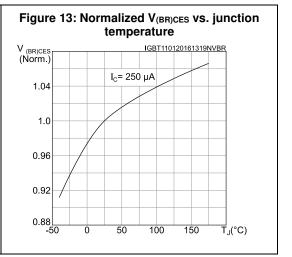


Figure 14: Capacitance variations

C
(pF)

10<sup>2</sup>

10<sup>1</sup>

f = 1 MHz

C
C
res

10<sup>0</sup>

10<sup>-1</sup>

10<sup>0</sup>

10<sup>1</sup>

10<sup>2</sup>

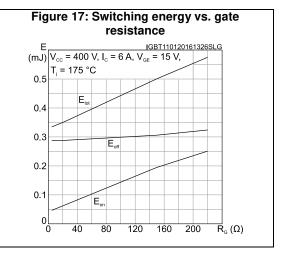
V<sub>CE</sub> (V)

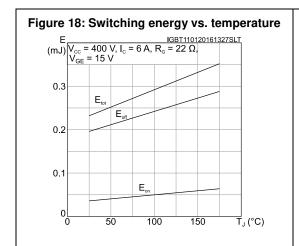
Figure 15: Gate charge vs. gate-emitter voltage

V<sub>GE</sub> | IGBT110120161320GCGE | IGGT110120161320GCGE | IGBT110120161320GCGE | IGBT110120161320GCGE | IGBT110120161320GCGE | IGGT110120161320GCGE | IGGT110120161320GCGE | IGGT110120161320GCGE | IGGT110120161320GCGE | IGGT1101201

Figure 16: Switching energy vs. collector current

| Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector current | Collector cu





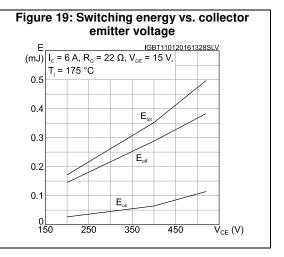


Figure 20: Short-circuit time and current vs.  $V_{\text{GE}}$ 

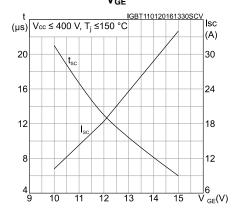


Figure 21: Switching times vs. collector current

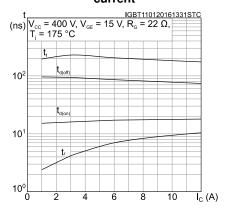


Figure 22: Switching times vs. gate resistance

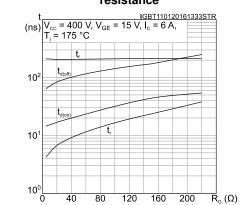


Figure 23: Reverse recovery current vs. diode current slope

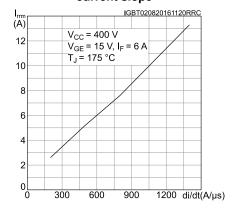


Figure 24: Reverse recovery time vs. diode current slope

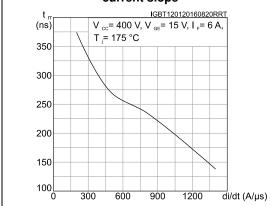
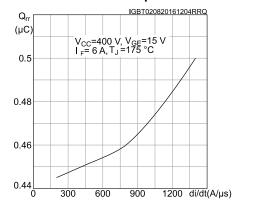
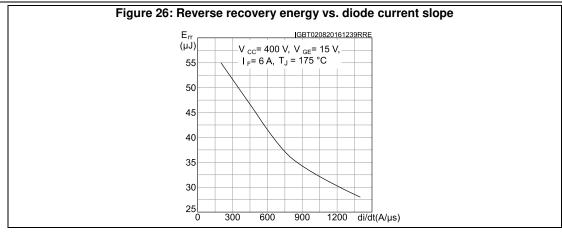
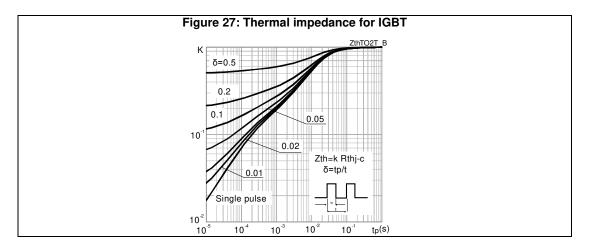
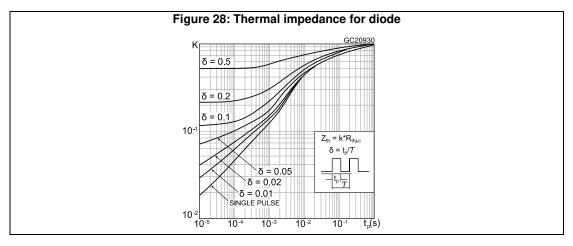


Figure 25: Reverse recovery charge vs. diode current slope



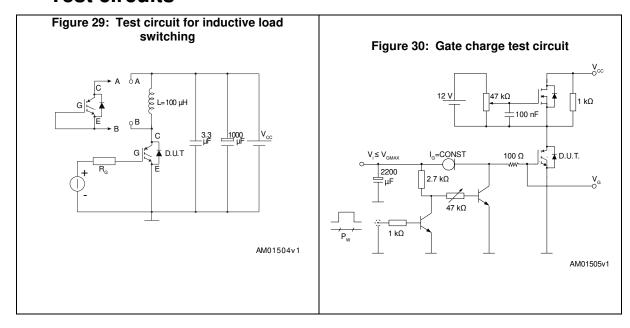


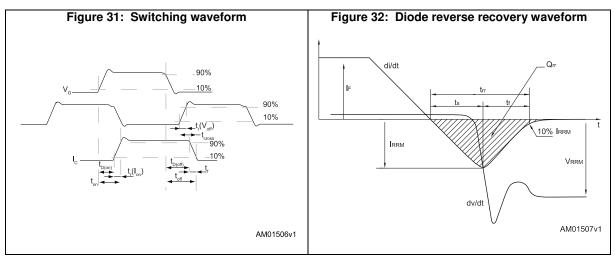




Test circuits STGD6M65DF2

## 3 Test circuits





STGD6M65DF2 Package information

## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

## 4.1 DPAK (TO-252) type A2 package information

Figure 33: DPAK (TO-252) type A2 package outline E -THERMAL PAD c2 - *E1* -L2 D **b**(2x) R C SEATING PLANE <u>A2</u> (L1) *V2* GAUGE PLANE 0,25

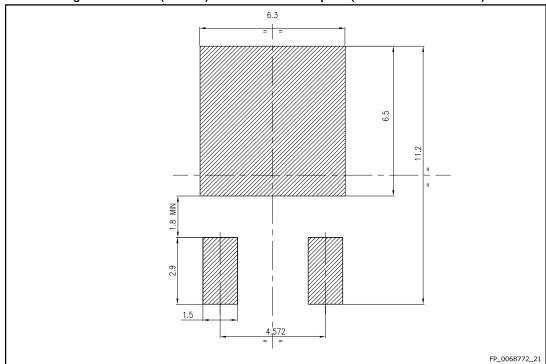
0068772\_type-A2\_rev21

Table 8: DPAK (TO-252) type A2 mechanical data

Dim	mm				
Dim.	Min.	Тур.	Max.		
А	2.20		2.40		
A1	0.90		1.10		
A2	0.03		0.23		
b	0.64		0.90		
b4	5.20		5.40		
С	0.45		0.60		
c2	0.48		0.60		
D	6.00		6.20		
D1	4.95	5.10	5.25		
Е	6.40		6.60		
E1	5.10	5.20	5.30		
е	2.16	2.28	2.40		
e1	4.40		4.60		
Н	9.35		10.10		
L	1.00		1.50		
L1	2.60	2.80	3.00		
L2	0.65	0.80	0.95		
L4	0.60		1.00		
R		0.20			
V2	0°		8°		

Package information STGD6M65DF2

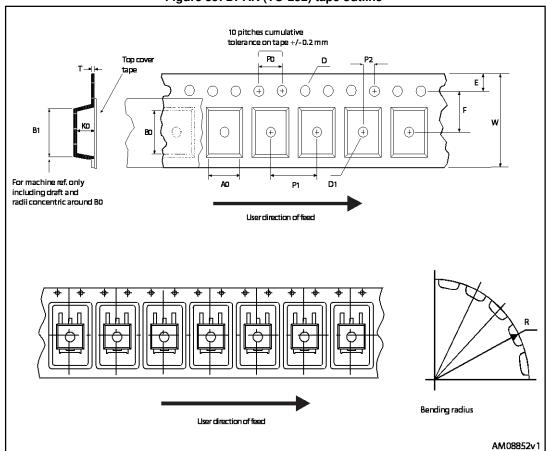




STGD6M65DF2 Package information

## 4.2 DPAK (TO-252) packing information

Figure 35: DPAK (TO-252) tape outline



A 40mm min. access hole at slot location

Tape slot in core for tape start 2.5mm min. width

Figure 36: DPAK (TO-252) reel outline

Table 9: DPAK (TO-252) tape and reel mechanical data

AM06038v1

	Таре			Reel	
Dim	m	mm		ı	nm
Dim.	Min.	Max.	Dim.	Min.	Max.
A0	6.8	7	А		330
В0	10.4	10.6	В	1.5	
B1		12.1	С	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
E	1.65	1.85	N	50	
F	7.4	7.6	Т		22.4
K0	2.55	2.75			
P0	3.9	4.1	Bas	e qty.	2500
P1	7.9	8.1	Bull	k qty.	2500
P2	1.9	2.1			
R	40				
Т	0.25	0.35			
W	15.7	16.3			

STGD6M65DF2 Revision history

# 5 Revision history

Table 10: Document revision history

Date	Revision	Changes	
30-Nov-2015	1	First release.	
13-Jan-2016	2	Modified: Table 4: "Static characteristics", Table 5: "Dynamic characteristics", Table 6: "IGBT switching characteristics (inductive load)" and Table 7: "Diode switching characteristics (inductive load)"	
		Added: Section 2.1: "Electrical characteristics (curves)"	
		Minor text changes	
04-Aug-2016	-2016 3	Updated: Table 2: "Absolute maximum ratings", Table 4: "Static characteristics", Table 6: "IGBT switching characteristics (inductive load)", Table 7: "Diode switching characteristics (inductive load)".	
		Updated Figure 9: "Forward bias safe operating area", Figure 12: "Normalized VGE(th) vs. junction temperature", Figure 20: "Short-circuit time and current vs. VGE", Figure 23: "Reverse recovery current vs. diode current slope".	
		Changed: Figure 25: "Reverse recovery charge vs. diode current slope", and Figure 26: "Reverse recovery energy vs. diode current slope".	
		Document status promoted from preliminary to production data.	

#### **IMPORTANT NOTICE - PLEASE READ CAREFULLY**

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2016 STMicroelectronics - All rights reserved